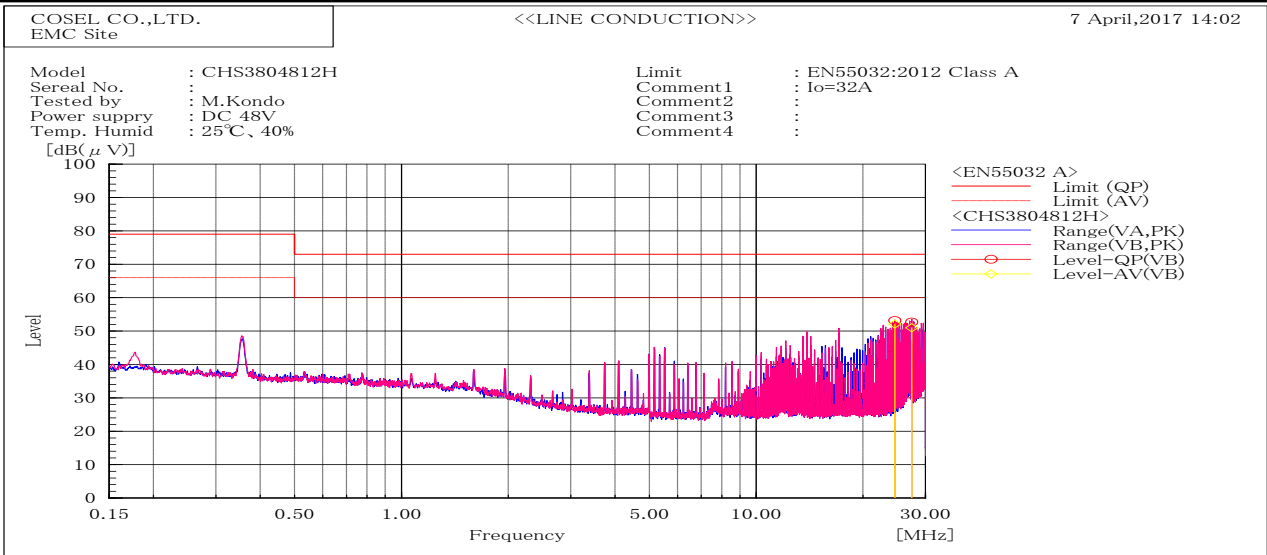
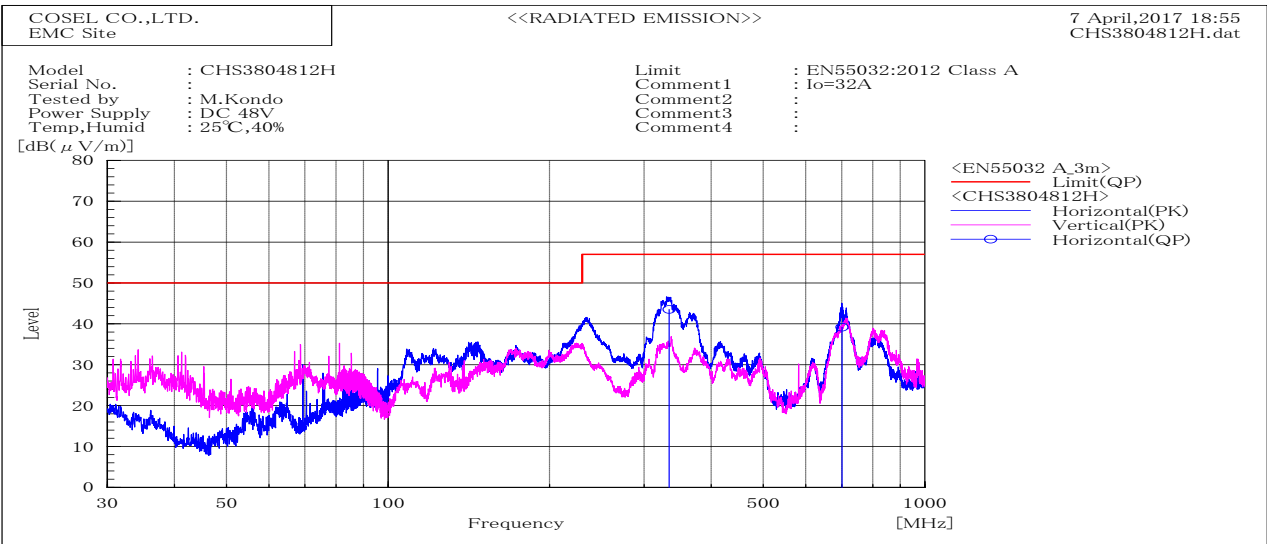


DATA SHEET		Date	07-Apr-17
Model	CHS3804812H	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo



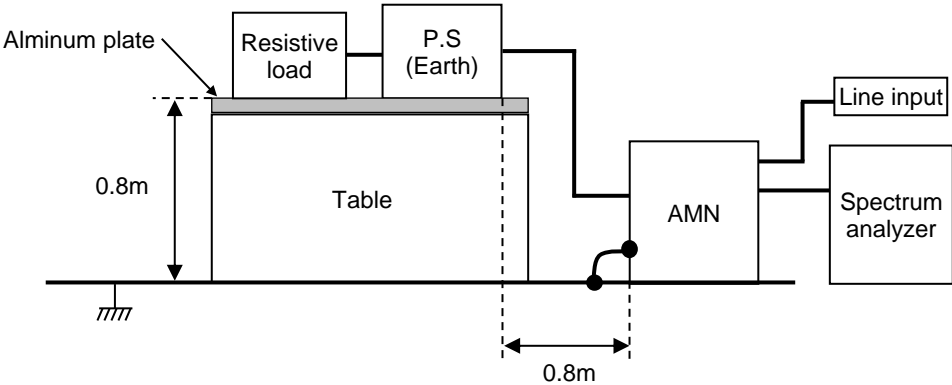
Frequency MHz	Line Phase	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
24.5845	VB	53.1	52.1	73	60	19.9	7.9	Pass	
27.44315	VB	52.7	51	73	60	20.3	9	Pass	



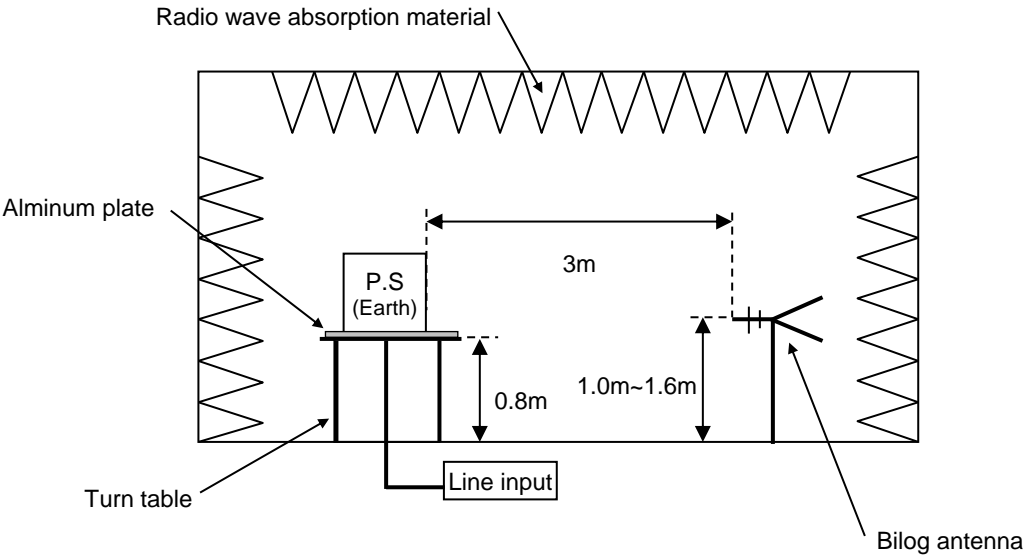
Frequency MHz	Polarization	Stability	Reading dB(uV)	Limit dB(uV/m)	Margin dB(uV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
333.772	H	Stable	43.5	57.0	13.5	Pass	109	336	
700.960	H	Stable	39.2	57.0	17.8	Pass	111	331	

DATA SHEET		Date	07-Apr-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo

1. Line conduction



2. Radiated emission



Conditions

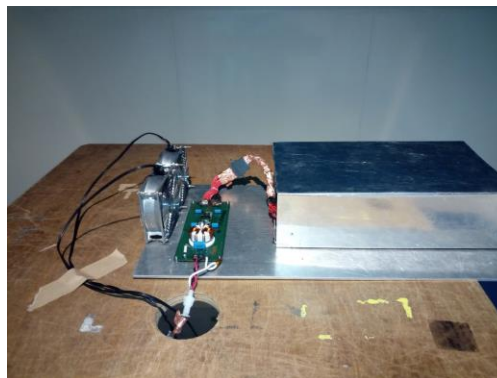
Test : EMI
Model Name : CHS380 Series

Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



Testing circuitry

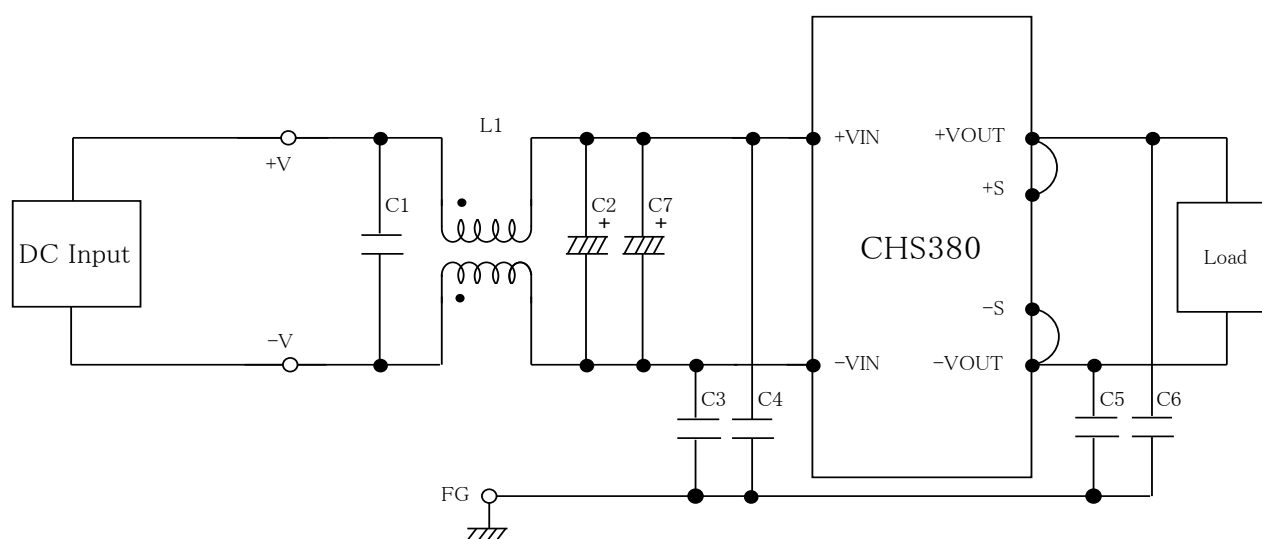


Fig.1 Testing circuitry

L1 : 1mH SC-20-10JH (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2,C7 : 100V 100 μ F PWseries (nichicon)
C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)